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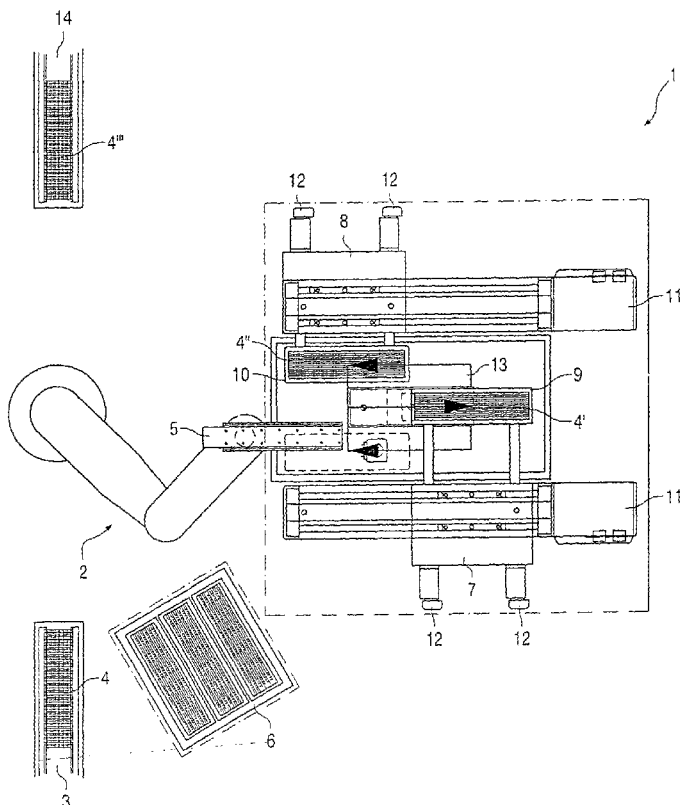
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(54) Title: DEVICE AND METHOD FOR TESTING ELECTRONIC COMPONENTS



(57) Abstract: The invention relates to a device for testing electronic components, comprising: a testing head, and means for bringing the components for testing into contact with the testing head, characterized in that the means for bringing the components for testing into contact with the testing head comprise at least two positioning units which are adapted for co-action with the common testing head. The invention also relates to a method for performing a test measurement.

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